Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
11	7554	(test\$4 same (IC or (integrated adj circuit))) and pattern and chip and pack\$5	US-PGPUB; USPAT; USOCR; EPO: JPO; DERWENT; IBM_TDB	OR	ON	2005/11/13 09:35
L2	2716	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/13 09:36
13	113	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/13 12:07
L4	8	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2005/11/13 09:38
L5	72	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/13 10:12
L6	62	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/13 10:57
L7.	3	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct\$4 and partition\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/13 10:15
L8	62	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct\$4 and function\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/13 11:34

L9	20	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct\$4 and function\$3 and (partition\$3 or divid\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/13 11:35
L10	90	(test\$4:same:(IC or:(integrated:adj:circuit)):same:pattern):and	USPAT; USOCR; EPO; JPO;	OR	ON	2005/11/13 12:08